Intel - 5SEE9H40I3N Datasheet





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Details

Product Status	Obsolete
Number of LABs/CLBs	317000
Number of Logic Elements/Cells	840000
Total RAM Bits	53248000
Number of I/O	696
Number of Gates	-
Voltage - Supply	0.82V ~ 0.88V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1517-BBGA, FCBGA
Supplier Device Package	1517-HBGA (45x45)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5see9h40i3n

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			Calibration Accuracy					
Symbol	Description	Conditions	C1	C2,12	C3,I3, I3YY	C4,14	Unit	
50-Ω R _S	Internal series termination with calibration (50- Ω setting)	V _{CCI0} = 3.0, 2.5, 1.8, 1.5, 1.2 V	±15	±15	±15	±15	%	
34-Ω and 40-Ω R _S	Internal series termination with calibration (34- Ω and 40- Ω setting)	V _{CCI0} = 1.5, 1.35, 1.25, 1.2 V	±15	±15	±15	±15	%	
48-Ω, 60-Ω, 80-Ω, and 240-Ω R _S	Internal series termination with calibration (48- Ω , 60- Ω , 80- Ω , and 240- Ω setting)	V _{CCI0} = 1.2 V	.2 V ±15 ±15		±15	±15	%	
50-Ω R _T	Internal parallel termination with calibration (50-Ω setting)	V _{CCIO} = 2.5, 1.8, 1.5, 1.2 V	-10 to +40	-10 to +40	-10 to +40	-10 to +40	%	
20- $Ω$, 30- $Ω$, 40- $Ω$,60- $Ω$, and 120- $Ω$ R _T	Internal parallel termination with calibration ($20 \cdot \Omega$, $30 \cdot \Omega$, $40 \cdot \Omega$, $60 \cdot \Omega$, and $120 \cdot \Omega$ setting)	V _{CCI0} = 1.5, 1.35, 1.25 V	-10 to +40	-10 to +40	-10 to +40	-10 to +40	%	
60-Ω and 120-Ω R_T	Internal parallel termination with calibration (60- Ω and 120- Ω setting)	V _{CCI0} = 1.2	-10 to +40	-10 to +40	-10 to +40	-10 to +40	%	
$\begin{array}{l} \textbf{25-}\Omega\\ \textbf{R}_{S_left_shift} \end{array}$	Internal left shift series termination with calibration (25- Ω R _{S_left_shift} setting)	V _{CCI0} = 3.0, 2.5, 1.8, 1.5, 1.2 V	±15	±15	±15	±15	%	

Table 11. OCT Calibration Accurat	y Specifications for Stratix V Devices ⁽¹⁾ ((Part 2 of 2)
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Note to Table 11:

(1) OCT calibration accuracy is valid at the time of calibration only.

Table 12 lists the Stratix V OCT without calibration resistance to PVT changes.

Symbol			Resistance Tolerance					
	Description	Conditions	C1	C2,I2	C3, I3, I3YY	C4, I4	Unit	
25-Ω R, 50-Ω R _S	Internal series termination without calibration (25- Ω setting)	$V_{CCIO} = 3.0$ and 2.5 V	±30	±30	±40	±40	%	
25-Ω R _S	Internal series termination without calibration (25-Ω setting)	$V_{CCI0} = 1.8$ and 1.5 V	±30	±30	±40	±40	%	
25-Ω R _S	Internal series termination without calibration (25-Ω setting)	V _{CCI0} = 1.2 V	±35	±35	±50	±50	%	

Symbol	Description	V _{CCIO} (V)	Typical	Unit
		3.0	0.189	
		2.5	0.208	
dR/dT	OCT variation with temperature without recalibration	1.8	0.266	%/°C
	without robalibration	1.5	0.273	
		1.2	0.317	

Table 13. OCT Variation after Power-Up Calibration for Stratix V Devices (Part 2 of 2)⁽¹⁾

Note to Table 13:

(1) Valid for a V_{CCIO} range of $\pm 5\%$ and a temperature range of 0° to 85°C.

Pin Capacitance

Table 14 lists the Stratix V device family pin capacitance.

Table 14. Pin Capacitance for Stratix V Devices

Symbol	Description	Value	Unit
C _{IOTB}	Input capacitance on the top and bottom I/O pins	6	pF
C _{IOLR}	Input capacitance on the left and right I/O pins	6	рF
C _{OUTFB}	Input capacitance on dual-purpose clock output and feedback pins	6	рF

Hot Socketing

Table 15 lists the hot socketing specifications for Stratix V devices.

Table 15.	Hot Socketing Specifications for Stratix V Devices
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Symbol	Description	Maximum
I _{IOPIN (DC)}	DC current per I/O pin	300 μA
I _{IOPIN (AC)}	AC current per I/O pin	8 mA ⁽¹⁾
I _{XCVR-TX (DC)}	DC current per transceiver transmitter pin	100 mA
I _{XCVR-RX (DC)}	DC current per transceiver receiver pin	50 mA

Note to Table 15:

(1) The I/O ramp rate is 10 ns or more. For ramp rates faster than 10 ns, $|I_{10PIN}| = C dv/dt$, in which C is the I/O pin capacitance and dv/dt is the slew rate.

Symbol/ Description	Conditions	Transceiver Speed Grade 1			Transceiver Speed Grade 2			Trai	Unit		
		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
Spread-spectrum downspread	PCle	_	0 to 0.5	_	_	0 to 0.5		_	0 to 0.5	_	%
On-chip termination resistors ⁽²¹⁾	_	_	100		_	100		_	100		Ω
Absolute V _{MAX} ⁽⁵⁾	Dedicated reference clock pin	_	_	1.6	_	_	1.6	_	_	1.6	V
	RX reference clock pin	_	_	1.2	_		1.2		_	1.2	
Absolute V_{MIN}	—	-0.4	—		-0.4	—	—	-0.4	—	—	V
Peak-to-peak differential input voltage	_	200	_	1600	200	_	1600	200	_	1600	mV
VICM (AC	Dedicated reference clock pin	1050/	1000/90	00/850 ⁽²⁾	1050/1000/900/850 (2)			1050/	mV		
coupled) ⁽³⁾	RX reference clock pin	1.0/0.9/0.85 ⁽⁴⁾			1.0/0.9/0.85 ⁽⁴⁾			1.	V		
V _{ICM} (DC coupled)	HCSL I/O standard for PCIe reference clock	250		550	250		550	250		550	mV
	100 Hz	—	—	-70	—	—	-70	—	—	-70	dBc/Hz
Transmitter	1 kHz			-90			-90		—	-90	dBc/Hz
REFCLK Phase Noise	10 kHz	—	—	-100	—	—	-100	—	—	-100	dBc/Hz
(622 MHz) ⁽²⁰⁾	100 kHz			-110		—	-110	—	—	-110	dBc/Hz
	≥1 MHz	—	—	-120	—	—	-120	—	—	-120	dBc/Hz
Transmitter REFCLK Phase Jitter (100 MHz) ⁽¹⁷⁾	10 kHz to 1.5 MHz (PCle)	_	_	3	_	_	3	_	_	3	ps (rms)
R _{REF} (19)	_		1800 ±1%		_	1800 ±1%	_		180 0 ±1%		Ω
Transceiver Clocks	S										
fixedclk clock frequency	PCIe Receiver Detect		100 or 125	_	_	100 or 125	_	_	100 or 125	_	MHz

Table 23. Transceiver Specifications for Stratix V GX and GS Devices ⁽¹⁾ (Part 2 of 7)

Symbol/	Conditions	Transceiver Speed Grade 1			Transceiver Speed Grade 2			Trai	Unit		
Description		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
Reconfiguration clock (mgmt_clk_clk) frequency	_	100	_	125	100		125	100		125	MHz
Receiver											
Supported I/O Standards	_			1.4-V PCM	L, 1.5-V	PCML,	2.5-V PCM	L, LVPE	CL, and	d LVDS	
Data rate (Standard PCS) (9), (23)	_	600	_	12200	600	_	12200	600	_	8500/ 10312.5 (24)	Mbps
Data rate (10G PCS) ^{(9),} ⁽²³⁾		600	_	14100	600	_	12500	600	_	8500/ 10312.5 (24)	Mbps
Absolute V_{MAX} for a receiver pin (5)		_	_	1.2	—	_	1.2	—	_	1.2	V
Absolute V _{MIN} for a receiver pin	_	-0.4	_		-0.4	_	_	-0.4	_	_	V
Maximum peak- to-peak differential input voltage V _{ID} (diff p- p) before device configuration ⁽²²⁾	_	_	_	1.6	_	_	1.6	_	_	1.6	V
Maximum peak- to-peak	V _{CCR_GXB} = 1.0 V/1.05 V (V _{ICM} = 0.70 V)	_	_	2.0	_	_	2.0	_	_	2.0	V
differential input voltage V_{ID} (diff p- p) after device configuration ⁽¹⁸⁾ ,	$V_{CCR_GXB} = 0.90 V$ (V _{ICM} = 0.6 V)	_	_	2.4	_	_	2.4	_	_	2.4	V
(22)	$V_{CCR_GXB} = 0.85 V$ (V _{ICM} = 0.6 V)			2.4			2.4			2.4	V
Minimum differential eye opening at receiver serial input pins ^{(6), (22),} (27)	_	85		_	85	_	_	85	_	_	mV

Table 23. Transceiver Specifications for Stratix V GX and GS Devices ⁽¹⁾ (Part 3 of 7)

Symbol/	Conditions	Transceiver Speed Grade 1			Transceiver Speed Grade 2			Trar	Unit		
Description		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
	DC Gain Setting = 0		0	_	_	0		_	0	_	dB
	DC Gain Setting = 1	_	2	_	—	2	_	_	2	_	dB
Programmable DC gain	DC Gain Setting = 2	_	4	_	_	4	_	_	4	_	dB
	DC Gain Setting = 3	_	6	_	_	6	_	_	6	_	dB
	DC Gain Setting = 4	_	8	_	_	8	_	_	8	—	dB
Transmitter											
Supported I/O Standards	_				-	I.4-V ar	nd 1.5-V PC	ML			
Data rate (Standard PCS)	_	600	_	12200	600	_	12200	600	_	8500/ 10312.5 (24)	Mbps
Data rate (10G PCS)	_	600	_	14100	600		12500	600		8500/ 10312.5 (24)	Mbps
	85-Ω setting		85 ± 20%	_	_	85 ± 20%		_	85 ± 20%	_	Ω
Differential on-	100-Ω setting	_	100 ± 20%	_	_	100 ± 20%	_	_	100 ± 20%	_	Ω
chip termination resistors	120-Ω setting	_	120 ± 20%			120 ± 20%		_	120 ± 20%		Ω
	150-Ω setting		150 ± 20%			150 ± 20%			150 ± 20%		Ω
V _{OCM} (AC coupled)	0.65-V setting		650		_	650		_	650	_	mV
V _{OCM} (DC coupled)	_		650		_	650		_	650	_	mV
Rise time (7)	20% to 80%	30		160	30		160	30		160	ps
Fall time ⁽⁷⁾	80% to 20%	30		160	30		160	30		160	ps
Intra-differential pair skew	Tx V _{CM} = 0.5 V and slew rate of 15 ps			15			15			15	ps
Intra-transceiver block transmitter channel-to- channel skew	x6 PMA bonded mode			120			120			120	ps

Table 23. Transceiver Specifications for Stratix V GX and GS Devices ⁽¹⁾ (Part 5 of 7)

Table 23. Transceiver Specifications for Stratix V GX and GS Devices ⁽¹⁾ (Part 6 of 7)

Symbol/	Conditions	Trai	isceive Grade	r Speed 1	Trar	isceive Grade	r Speed 2	Tran	isceive Grade	er Speed e 3	Unit
Description		Min Typ M		Max	Min Typ		Max	Min Ty		Max	
Inter-transceiver block transmitter channel-to- channel skew	xN PMA bonded mode			500	_		500	_		500	ps
CMU PLL											
Supported Data Range	_	600		12500	600	_	12500	600	_	8500/ 10312.5 (24)	Mbps
t _{pll_powerdown} ⁽¹⁵⁾	_	1		—	1	—	—	1	—	—	μs
t _{pll_lock} (16)	_		_	10	—	_	10	—	—	10	μs
ATX PLL	1										
	VCO post-divider L=2	8000		14100	8000	_	12500	8000	_	8500/ 10312.5 (24)	Mbps
Current and Date	L=4	4000	_	7050	4000	_	6600	4000	—	6600	Mbps
Supported Data Rate Range	L=8	2000	_	3525	2000	_	3300	2000	_	3300	Mbps
nate nange	L=8, Local/Central Clock Divider =2	1000	_	1762.5	1000		1762.5	1000		1762.5	Mbps
t _{pll_powerdown} (15)	_	1		_	1			1	—	_	μs
t _{pll_lock} ⁽¹⁶⁾	—			10	—	—	10	—	—	10	μs
fPLL	•			•					•		
Supported Data Range	_	600	_	3250/ 3125 ⁽²⁵⁾	600	_	3250/ 3125 ⁽²⁵⁾	600	_	3250/ 3125 ⁽²⁵⁾	Mbps
t _{pll_powerdown} ⁽¹⁵⁾	_	1	_	_	1	_	—	1	—	—	μs

Table 28. Transceiver Specifications for Stratix V GT Devices (Part 2 of 5)⁽¹⁾

Symbol/	Conditions		Transceive Speed Grade			Fransceive Deed Grade		Unit
Description		Min	Тур	Max	Min	Тур	Max	Ī
	100 Hz			-70			-70	
Transmitter REFCLK	1 kHz		_	-90	_	_	-90	-
Phase Noise (622	10 kHz		_	-100	_	_	-100	dBc/Hz
MHz) ⁽¹⁸⁾	100 kHz		—	-110	_	—	-110	-
	\geq 1 MHz		—	-120	_	—	-120	-
Transmitter REFCLK Phase Jitter (100 MHz) ⁽¹⁵⁾	10 kHz to 1.5 MHz (PCIe)		_	3	_		3	ps (rms)
RREF ⁽¹⁷⁾	—		1800 ± 1%	_	_	1800 ± 1%	_	Ω
Transceiver Clocks								
fixedclk clock frequency	PCIe Receiver Detect		100 or 125	_	_	100 or 125	_	MHz
Reconfiguration clock (mgmt_clk_clk) frequency	_	100	_	125	100	_	125	MHz
Receiver				•				
Supported I/O Standards	—		1.4-V PCMI	_, 1.5-V PCM	L, 2.5-V PCI	ML, LVPEC	L, and LVDS	3
Data rate (Standard PCS) ⁽²¹⁾	GX channels	600	_	8500	600	_	8500	Mbps
Data rate (10G PCS) ⁽²¹⁾	GX channels	600	_	12,500	600	_	12,500	Mbps
Data rate	GT channels	19,600	—	28,050	19,600	—	25,780	Mbps
Absolute V _{MAX} for a receiver pin ⁽³⁾	GT channels	_	_	1.2	_	_	1.2	V
Absolute V _{MIN} for a receiver pin	GT channels	-0.4	_	_	-0.4		_	V
Maximum peak-to-peak	GT channels	_	—	1.6	—	—	1.6	V
differential input voltage V _{ID} (diff p-p) before device configuration ⁽²⁰⁾	GX channels				(8)			
	GT channels							
Maximum peak-to-peak differential input voltage V_{ID} (diff p-p) after device configuration (¹⁶), (²⁰)	V _{CCR_GTB} = 1.05 V (V _{ICM} = 0.65 V)	—	-	2.2	_	_	2.2	V
oomguration (), ()	GX channels		•	•	(8)			
Minimum differential	GT channels	200	_		200			mV
eye opening at receiver serial input pins ⁽⁴⁾ , ⁽²⁰⁾	GX channels				(8)			

Table 28. Transceiver Specifications for Stratix V GT Devices (Part 4 of 5) ⁽¹⁾
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Symbol/	Conditions		Transceive peed Grade		ן St	Unit		
Description		Min	Тур	Max	Min	Тур	Max	
Data rate	GT channels	19,600		28,050	19,600		25,780	Mbps
Differential on-chip	GT channels		100	_		100		Ω
termination resistors	GX channels		1	1	(8)		11	
	GT channels		500	_		500	—	mV
V_{OCM} (AC coupled)	GX channels		1	1	(8)		11	
Dies/Fall times	GT channels	_	15	_		15	—	ps
Rise/Fall time	GX channels				(8)		1	
Intra-differential pair skew	GX channels				(8)			
Intra-transceiver block transmitter channel-to- channel skew	GX channels				(8)			
Inter-transceiver block transmitter channel-to- channel skew	GX channels				(8)			
CMU PLL	· · · · · ·							
Supported Data Range	—	600	—	12500	600	—	8500	Mbps
t _{pll_powerdown} (13)	—	1	—	—	1	_	—	μs
t _{pll_lock} ⁽¹⁴⁾	—	_	—	10	—	_	10	μs
ATX PLL								
	VCO post- divider L=2	8000	_	12500	8000	_	8500	Mbps
	L=4	4000	—	6600	4000	_	6600	Mbps
Supported Data Rate	L=8	2000	—	3300	2000	-	3300	Mbps
Range for GX Channels	L=8, Local/Central Clock Divider =2	1000	_	1762.5	1000	_	1762.5	Mbps
Supported Data Rate Range for GT Channels	VCO post- divider L=2	9800	_	14025	9800	_	12890	Mbps
t _{pll_powerdown} ⁽¹³⁾	—	1	—	—	1	—	—	μs
t _{pll_lock} ⁽¹⁴⁾	—		—	10	—	—	10	μs
fPLL							· ·	
Supported Data Range	_	600		3250/ 3.125 ⁽²³⁾	600	_	3250/ 3.125 ⁽²³⁾	Mbps
t _{pll_powerdown} (13)		1	_		1			μs

Table 29 shows the V_{OD} settings for the GT channel.

Table 29.	Typical Von Setting	g for GT Channel, T	EX Termination = 100 Ω
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Symbol	V _{OD} Setting	V _{op} Value (mV)
	0	0
	1	200
\mathbf{V}_{0D} differential peak to peak typical (1)	2	400
VOD unicicilitat peak to peak typical (*)	3	600
	4	800
	5	1000

Note:

(1) Refer to Figure 4.

PLL Specifications

Table 31 lists the Stratix V PLL specifications when operating in both the commercial junction temperature range (0° to 85° C) and the industrial junction temperature range (-40° to 100° C).

Table 31. PLL Specifications for Stratix V Devices (Part 1 of 3)

Symbol	Parameter	Min	Тур	Max	Unit
	Input clock frequency (C1, C2, C2L, I2, and I2L speed grades)	5	_	800 (1)	MHz
f _{IN}	Input clock frequency (C3, I3, I3L, and I3YY speed grades)	5	_	800 (1)	MHz
	Input clock frequency (C4, I4 speed grades)	5	_	650 ⁽¹⁾	MHz
f _{INPFD}	Input frequency to the PFD	5	—	325	MHz
f _{finpfd}	Fractional Input clock frequency to the PFD	50	—	160	MHz
	PLL VCO operating range (C1, C2, C2L, I2, I2L speed grades)	600	_	1600	MHz
f _{VCO}	PLL VCO operating range (C3, I3, I3L, I3YY speed grades)	600	_	1600	MHz
	PLL VCO operating range (C4, I4 speed grades)	600	—	1300	MHz
t _{einduty}	Input clock or external feedback clock input duty cycle	40		60	%
	Output frequency for an internal global or regional clock (C1, C2, C2L, I2, I2L speed grades)	—	_	717 ⁽²⁾	MHz
f _{out}	Output frequency for an internal global or regional clock (C3, I3, I3L speed grades)	_	_	650 ⁽²⁾	MHz
Output frequency for an internal global or regional clock (C4, I4 speed grades)		_	_	580 ⁽²⁾	MHz
	Output frequency for an external clock output (C1, C2, C2L, I2, I2L speed grades)	_	_	800 (2)	MHz
f _{out_ext}	Output frequency for an external clock output (C3, I3, I3L speed grades)	_	_	667 ⁽²⁾	MHz
	Output frequency for an external clock output (C4, I4 speed grades)	_	_	553 ⁽²⁾	MHz
t _{outduty}	Duty cycle for a dedicated external clock output (when set to 50%)	45	50	55	%
t _{FCOMP}	External feedback clock compensation time	_	—	10	ns
f _{dyconfigclk}	Dynamic Configuration Clock used for <code>mgmt_clk</code> and <code>scanclk</code>	_	_	100	MHz
t _{LOCK}	Time required to lock from the end-of-device configuration or deassertion of areset	_	_	1	ms
t _{olock}	Time required to lock dynamically (after switchover or reconfiguring any non-post-scale counters/delays)	_	_	1	ms
	PLL closed-loop low bandwidth		0.3	—	MHz
f _{CLBW}	PLL closed-loop medium bandwidth	_	1.5		MHz
	PLL closed-loop high bandwidth (7)		4	—	MHz
t _{PLL_PSERR}	Accuracy of PLL phase shift			±50	ps
t _{areset}	Minimum pulse width on the areset signal	10	_		ns

Peformance										
Mode	C1	C2, C2L	12, 12L	C3	13, 13L, 13YY	C4	14	Unit		
Modes using Three DSPs										
One complex 18 x 25	425	425	415	340	340	275	265	MHz		
Modes using Four DSPs										
One complex 27 x 27	465	465	465	380	380	300	290	MHz		

Table 32. Block Performance Specifications for Stratix V DSP Devices (Part 2 of 2)

Memory Block Specifications

Table 33 lists the Stratix V memory block specifications.

Table 33. Memory Block Performance Specifications for Stratix V Devices ^{(1), (2)} (Part 1 of 2)

		Resour	ces Used	Performance							
Memory	Mode	ALUTS	Memory	C1	C2, C2L	C3	C4	12, 12L	13, 13L, 13YY	14	Unit
	Single port, all supported widths	0	1	450	450	400	315	450	400	315	MHz
MLAB	Simple dual-port, x32/x64 depth	0	1	450	450	400	315	450	400	315	MHz
IVILAD	Simple dual-port, x16 depth ⁽³⁾	0	1	675	675	533	400	675	533	400	MHz
	ROM, all supported widths	0	1	600	600	500	450	600	500	450	MHz

0h.a.l	Oanditiana	C1			C2,	C2L, I	2, I2L	C3, I3, I3L, I3YY			C4,14			11
Symbol	Conditions	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
Transmitter	•													•
True Differential I/O Standards	SERDES factor J = 3 to 10 (9), (11), (12), (13), (14), (15), (16)	(6)	_	1600	(6)	_	1434	(6)	_	1250	(6)	_	1050	Mbps
	$\begin{array}{c} \text{SERDES factor J} \\ \geq 4 \end{array}$													
	LVDS TX with DPA ⁽¹²⁾ , ⁽¹⁴⁾ , ⁽¹⁵⁾ , ⁽¹⁶⁾	(6)		1600	(6)		1600	(6)	_	1600	(6)	_	1250	Mbps
- f _{HSDR} (data rate)	SERDES factor J = 2,	(6)		(7)	(6)		(7)	(6)		(7)	(6)		(7)	Mbps
	uses DDR Registers	(0)	_	(7)	(0)		(7)	(0)	_	(7)	(0)	_	(7)	wups
	SERDES factor J = 1, uses SDR Register	(6)	_	(7)	(6)	_	(7)	(6)		(7)	(6)		(7)	Mbps
Emulated Differential I/O Standards with Three External Output Resistor Networks - f _{HSDR} (data rate) ⁽¹⁰⁾	SERDES factor J = 4 to 10 (17)	(6)		1100	(6)		1100	(6)		840	(6)		840	Mbps
t _{x Jitter} - True Differential	Total Jitter for Data Rate 600 Mbps - 1.25 Gbps	_	_	160	_	_	160			160	_		160	ps
I/O Standards	Total Jitter for Data Rate < 600 Mbps	_	_	0.1	_	_	0.1	_	_	0.1	_	_	0.1	UI
t _{x Jitter} - Emulated Differential I/O Standards	Total Jitter for Data Rate 600 Mbps - 1.25 Gbps	_	_	300	_	_	300	_	_	300	_	_	325	ps
with Three External Output Resistor Network	Total Jitter for Data Rate < 600 Mbps	_		0.2			0.2			0.2	_		0.25	UI

Table 36. High-Speed I/O Specifications for Stratix V Devices (1), (2) (Part 2 of 4)

Speed Grade	Min	Max	Unit
C4,I4	8	16	ps

Table 40. DQS Phase Offset Delay Per Setting for Stratix V Devices ^{(1), (2)} (Part 2 of 2)

Notes to Table 40:

(1) The typical value equals the average of the minimum and maximum values.

(2) The delay settings are linear with a cumulative delay variation of 40 ps for all speed grades. For example, when using a -2 speed grade and applying a 10-phase offset setting to a 90° phase shift at 400 MHz, the expected average cumulative delay is [625 ps + (10 × 10 ps) ± 20 ps] = 725 ps ± 20 ps.

Table 41 lists the DQS phase shift error for Stratix V devices.

Table 41. DQS Phase Shift Error Specification for DLL-Delayed Clock (t_{DQS_PSERR}) for Stratix V Devices ⁽¹⁾

Number of DQS Delay Buffers	C1	C2, C2L, I2, I2L	C3, I3, I3L, I3YY	C4,14	Unit
1	28	28	30	32	ps
2	56	56	60	64	ps
3	84	84	90	96	ps
4	112	112	120	128	ps

Notes to Table 41:

(1) This error specification is the absolute maximum and minimum error. For example, skew on three DQS delay buffers in a -2 speed grade is ± 78 ps or ± 39 ps.

Table 42 lists the memory output clock jitter specifications for Stratix V devices.

Clock Network	Parameter	Symbol	C1 C2, C2L, I2, I2L		, 12, 12L	C3, I3, I3L, I3YY		C4,14		Unit	
			Min	Max	Min	Max	Min	Max	Min	Max	
Regional	Clock period jitter	t _{JIT(per)}	-50	50	-50	50	-55	55	-55	55	ps
	Cycle-to-cycle period jitter	$t_{\rm JIT(cc)}$	-100	100	-100	100	-110	110	-110	110	ps
	Duty cycle jitter	$t_{JIT(duty)}$	-50	50	-50	50	-82.5	82.5	-82.5	82.5	ps
	Clock period jitter	t _{JIT(per)}	-75	75	-75	75	-82.5	82.5	-82.5	82.5	ps
Global	Cycle-to-cycle period jitter	$t_{\text{JIT(cc)}}$	-150	150	-150	150	-165	165	-165	165	ps
	Duty cycle jitter	$t_{JIT(duty)}$	-75	75	-75	75	-90	90	-90	90	ps

Clock	Parameter Symbo		C1		C2, C2L, I2, I2L		C3, I3, I3L, I3YY		C4,14		Unit
Network			Min	Max	Min	Max	Min	Max	Min	Max	
	Clock period jitter	$t_{JIT(per)}$	-25	25	-25	25	-30	30	-35	35	ps
PHY Clock	Cycle-to-cycle period jitter	$t_{\text{JIT(cc)}}$	-50	50	-50	50	-60	60	-70	70	ps
	Duty cycle jitter	$t_{\text{JIT}(\text{duty})}$	-37.5	37.5	-37.5	37.5	-45	45	-56	56	ps

Table 42. Memory Output Clock Jitter Specification for Stratix V Devices (1), (Part 2 of 2) (2), (3)

Notes to Table 42:

(1) The clock jitter specification applies to the memory output clock pins generated using differential signal-splitter and DDIO circuits clocked by a PLL output routed on a PHY, regional, or global clock network as specified. Altera recommends using PHY clock networks whenever possible.

(2) The clock jitter specification applies to the memory output clock pins clocked by an integer PLL.

(3) The memory output clock jitter is applicable when an input jitter of 30 ps peak-to-peak is applied with bit error rate (BER) -12, equivalent to 14 sigma.

OCT Calibration Block Specifications

Table 43 lists the OCT calibration block specifications for Stratix V devices.

Table 43. OCT Calibration Block Specifications for Stratix V Devices

Symbol	Description	Min	Тур	Max	Unit
OCTUSRCLK	Clock required by the OCT calibration blocks		—	20	MHz
T _{OCTCAL}	Number of OCTUSRCLK clock cycles required for OCT $\rm R_S/R_T$ calibration	_	1000	_	Cycles
T _{OCTSHIFT}	Number of OCTUSRCLK clock cycles required for the OCT code to shift out	_	32	_	Cycles
T _{RS_RT}	Time required between the dyn_term_ctrl and oe signal transitions in a bidirectional I/O buffer to dynamically switch between OCT R_S and R_T (Figure 10)		2.5	_	ns

Figure 10 shows the timing diagram for the oe and dyn_term_ctrl signals.

Figure 10. Timing Diagram for oe and dyn_term_ctrl Signals



Table 50 lists the timing parameters for Stratix V devices for FPP configuration when the DCLK-to-DATA[] ratio is 1.

Table 50. FPP Timing Parameters for Stratix V Devices (1)

Symbol	Parameter	Minimum	Maximum	Units	
t _{CF2CD}	nCONFIG low to CONF_DONE low	—	600	ns	
t _{CF2ST0}	nCONFIG low to nSTATUS low	—	600	ns	
t _{CFG}	nCONFIG low pulse width	2	—	μS	
t _{status}	nSTATUS low pulse width	268	1,506 ⁽²⁾	μS	
t _{CF2ST1}	nCONFIG high to nSTATUS high	—	1,506 ⁽³⁾	μS	
t _{CF2CK} (6)	nCONFIG high to first rising edge on DCLK	1,506	_	μS	
t _{ST2CK} ⁽⁶⁾	nSTATUS high to first rising edge of DCLK	2	_	μS	
t _{DSU}	DATA [] setup time before rising edge on DCLK	5.5	_	ns	
t _{DH}	DATA [] hold time after rising edge on DCLK	0	_	ns	
t _{CH}	DCLK high time	$0.45\times1/f_{MAX}$	—	S	
t _{CL}	DCLK low time	$0.45\times1/f_{MAX}$	—	S	
t _{CLK}	DCLK period	1/f _{MAX}	_	S	
f	DCLK frequency (FPP ×8/×16)	—	125	MHz	
f _{MAX}	DCLK frequency (FPP ×32)	—	100	MHz	
t _{CD2UM}	CONF_DONE high to user mode ⁽⁴⁾	175	437	μS	
+	CONF_DONE high to CLKUSR enabled	4 × maximum			
t _{CD2CU}		DCLK period	—		
t _{CD2UMC}	CONF_DONE high to user mode with CLKUSR option on	$\begin{array}{c} t_{\text{CD2CU}} + \\ (8576 \times \text{CLKUSR} \\ \text{period}) \ ^{(5)} \end{array}$	_	_	

Notes to Table 50:

(1) Use these timing parameters when the decompression and design security features are disabled.

(2) This value is applicable if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.

(3) This value is applicable if you do not delay configuration by externally holding the nSTATUS low.

- (4) The minimum and maximum numbers apply only if you chose the internal oscillator as the clock source for initializing the device.
- (5) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the Initialization section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.
- (6) If nSTATUS is monitored, follow the t_{ST2CK} specification. If nSTATUS is not monitored, follow the t_{CF2CK} specification.

FPP Configuration Timing when DCLK-to-DATA [] > 1

Figure 13 shows the timing waveform for FPP configuration when using a MAX II device, MAX V device, or microprocessor as an external host. This waveform shows timing when the DCLK-to-DATA [] ratio is more than 1.



Figure 13. FPP Configuration Timing Waveform When the DCLK-to-DATA[] Ratio is >1 (1), (2)

Notes to Figure 13:

- (1) Use this timing waveform and parameters when the DCLK-to-DATA [] ratio is >1. To find out the DCLK-to-DATA [] ratio for your system, refer to Table 49 on page 55.
- (2) The beginning of this waveform shows the device in user mode. In user mode, nCONFIG, nSTATUS, and CONF_DONE are at logic high levels. When nCONFIG is pulled low, a reconfiguration cycle begins.
- (3) After power-up, the Stratix V device holds nSTATUS low for the time as specified by the POR delay.
- (4) After power-up, before and during configuration, CONF_DONE is low.
- (5) Do not leave DCLK floating after configuration. You can drive it high or low, whichever is more convenient.
- (6) "r" denotes the DCLK-to-DATA [] ratio. For the DCLK-to-DATA [] ratio based on the decompression and the design security feature enable settings, refer to Table 49 on page 55.
- (7) If needed, pause DCLK by holding it low. When DCLK restarts, the external host must provide data on the DATA [31..0] pins prior to sending the first DCLK rising edge.
- (8) To ensure a successful configuration, send the entire configuration data to the Stratix V device. CONF_DONE is released high after the Stratix V device receives all the configuration data successfully. After CONF_DONE goes high, send two additional falling edges on DCLK to begin initialization and enter user mode.
- (9) After the option bit to enable the INIT DONE pin is configured into the device, the INIT DONE goes low.

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Table 51 lists the timing parameters for Stratix V devices for FPP configuration when the DCLK-to-DATA[] ratio is more than 1.

Symbol	Parameter	Minimum	Maximum	Units
t _{CF2CD}	nCONFIG low to CONF_DONE low	—	600	ns
t _{CF2ST0}	nCONFIG low to nSTATUS low	—	600	ns
t _{CFG}	nCONFIG low pulse width	2	_	μS
t _{STATUS}	nSTATUS low pulse width	268	1,506 ⁽²⁾	μS
t _{CF2ST1}	nCONFIG high to nSTATUS high	—	1,506 ⁽²⁾	μS
t _{CF2CK} ⁽⁵⁾	nCONFIG high to first rising edge on DCLK	1,506	_	μS
t _{ST2CK} ⁽⁵⁾	nSTATUS high to first rising edge of DCLK	2	—	μS
t _{DSU}	DATA [] setup time before rising edge on DCLK	5.5		ns
t _{DH}	DATA [] hold time after rising edge on DCLK	N-1/f _{DCLK} ⁽⁵⁾		S
t _{CH}	DCLK high time	$0.45 imes 1/f_{MAX}$		S
t _{CL}	DCLK low time	$0.45\times1/f_{MAX}$		S
t _{CLK}	DCLK period	1/f _{MAX}		S
ſ	DCLK frequency (FPP ×8/×16)	—	125	MHz
f _{MAX}	DCLK frequency (FPP ×32)	—	100	MHz
t _R	Input rise time	—	40	ns
t _F	Input fall time	—	40	ns
t _{CD2UM}	CONF_DONE high to user mode ⁽³⁾	175	437	μS
t _{CD2CU}	CONF_DONE high to CLKUSR enabled	4 × maximum DCLK period	_	_
t _{CD2UMC}	CONF_DONE high to user mode with CLKUSR option on	t_{CD2CU} + (8576 × CLKUSR period) ⁽⁴⁾	_	_

Notes to Table 51:

- (1) Use these timing parameters when you use the decompression and design security features.
- (2) You can obtain this value if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.
- (3) The minimum and maximum numbers apply only if you use the internal oscillator as the clock source for initializing the device.
- (4) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the Initialization section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.
- (5) N is the ${\tt DCLK}\mbox{-to-DATA}$ ratio and $f_{{\tt DCLK}}$ is the ${\tt DCLK}$ frequency the system is operating.
- (6) If nSTATUS is monitored, follow the t_{ST2CK} specification. If nSTATUS is not monitored, follow the t_{CF2CK} specification.

Symbol	Parameter	Minimum	Maximum	Units
t _{CD2UM}	CONF_DONE high to user mode (3)	175	437	μS
t _{CD2CU}	CONF_DONE high to CLKUSR enabled	4 × maximum DCLK period	_	—
t _{CD2UMC}	CONF_DONE high to user mode with CLKUSR option on	t _{cd2cu} + (8576 × clkusr period)	_	—

Table 53. AS Timing Parameters for AS \times 1 and AS \times 4 Configurations in Stratix V Devices ^{(1), (2)} (Part 2 of 2)

Notes to Table 53:

(1) The minimum and maximum numbers apply only if you choose the internal oscillator as the clock source for initializing the device.

(2) t_{CF2CD}, t_{CF2ST0}, t_{CF2ST0}, t_{CF6}, t_{STATUS}, and t_{CF2ST1} timing parameters are identical to the timing parameters for PS mode listed in Table 54 on page 63.

(3) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on this pin, refer to the Initialization section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.

Passive Serial Configuration Timing

Figure 15 shows the timing waveform for a passive serial (PS) configuration when using a MAX II device, MAX V device, or microprocessor as an external host.

Figure 15. PS Configuration Timing Waveform ⁽¹⁾



Notes to Figure 15:

- (1) The beginning of this waveform shows the device in user mode. In user mode, nCONFIG, nSTATUS, and CONF_DONE are at logic high levels. When nCONFIG is pulled low, a reconfiguration cycle begins.
- (2) After power-up, the Stratix V device holds <code>nSTATUS</code> low for the time of the POR delay.
- (3) After power-up, before and during configuration, CONF DONE is low.
- (4) Do not leave DCLK floating after configuration. You can drive it high or low, whichever is more convenient.
- (5) DATAO is available as a user I/O pin after configuration. The state of this pin depends on the dual-purpose pin settings in the **Device and Pins Option**.
- (6) To ensure a successful configuration, send the entire configuration data to the Stratix V device. CONF_DONE is released high after the Stratix V device receives all the configuration data successfully. After CONF_DONE goes high, send two additional falling edges on DCLK to begin initialization and enter user mode.
- (7) After the option bit to enable the INIT DONE pin is configured into the device, the INIT DONE goes low.

Document Revision History

Table 61 lists the revision history for this chapter.

 Table 61. Document Revision History (Part 1 of 3)

Date	Version	Changes
June 2018	3.9	 Added the "Stratix V Device Overshoot Duration" figure.
		 Added a footnote to the "High-Speed I/O Specifications for Stratix V Devices" table.
		 Changed the minimum value for t_{CD2UMC} in the "PS Timing Parameters for Stratix V Devices" table.
		 Changed the condition for 100-Ω R_D in the "OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices" table.
April 2017	3.8	 Changed the minimum value for t_{CD2UMC} in the "AS Timing Parameters for AS '1 and AS '4 Configurations in Stratix V Devices" table
		 Changed the minimum value for t_{CD2UMC} in the "FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[] Ratio is >1" table.
		 Changed the minimum value for t_{CD2UMC} in the "FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[] Ratio is >1" table.
		 Changed the minimum number of clock cycles value in the "Initialization Clock Source Option and the Maximum Frequency" table.
June 2016	3.7	 Added the V_{ID} minimum specification for LVPECL in the "Differential I/O Standard Specifications for Stratix V Devices" table
Julie 2010		 Added the I_{OUT} specification to the "Absolute Maximum Ratings for Stratix V Devices" table.
December 2015	3.6	Added a footnote to the "High-Speed I/O Specifications for Stratix V Devices" table.
December 2015	15 3.5	 Changed the transmitter, receiver, and ATX PLL data rate specifications in the "Transceiver Specifications for Stratix V GX and GS Devices" table.
December 2015		 Changed the configuration .rbf sizes in the "Uncompressed .rbf Sizes for Stratix V Devices" table.
		• Changed the data rate specification for transceiver speed grade 3 in the following tables:
		 "Transceiver Specifications for Stratix V GX and GS Devices"
		 "Stratix V Standard PCS Approximate Maximum Date Rate"
		 "Stratix V 10G PCS Approximate Maximum Data Rate"
July 2015	3.4	 Changed the conditions for reference clock rise and fall time, and added a note to the "Transceiver Specifications for Stratix V GX and GS Devices" table.
		 Added a note to the "Minimum differential eye opening at receiver serial input pins" specification in the "Transceiver Specifications for Stratix V GX and GS Devices" table.
		 Changed the t_{co} maximum value in the "AS Timing Parameters for AS '1 and AS '4 Configurations in Stratix V Devices" table.
		 Removed the CDR ppm tolerance specification from the "Transceiver Specifications for Stratix V GX and GS Devices" table.